ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /C.L./

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Form PTO 1449 (Modified)		U.S. DEPARTMEN' PATENT AND TRA	T OF COMMERCE ADEMARK OFFICE	288247US2PCT	New U.S. PCT Application Based on PCT/JP04/08276			
				APPLICANT				1/3/-04/062/6
LIST OF	REFE	RENCES CITED BY A	PPLICANT	Shinya YOKODATE, et al.				
				FILING DATE	GROUP			
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				U.S. PATENT DOCUMENTS				
EXAMINER		DOCUMENT		1	T	SUB	F	ILING DATE
INITIAL		NUMBER	DATE	NAME	CLASS	CLASS CLASS IF APPROPRIATE		
	AA						_	
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		DOCUMENT	DATE	COUNTRY				LATION
	<u> </u>	NUMBER				YES	3	NO
	AG	39075/1995	07/14/95	JP	İ			NO
	AH	10-228250	08/25/98	JP .				NO
	Al	2001-143501	05/25/01	JP		<u> </u>		NO
	AJ	3068833	03/01/00	JP		ļ		NO
	AK	6-175591	06/24/94	JP			\longrightarrow	NO
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	AM	2004-159363	06/03/04	JP				NO
	AN	10-63227	03/06/98	JP (equivalent of US5751263)				NO
	AO	2004-88316	03/18/04	JP				NO
	AP	2003-218990	07/31/03	JP			·	NO
	AQ	2002-169198	06/14/02	JP				NO
	AR	2003-259182	09/12/03	JP (equivalent of US2003/164881)				NO
	AS	2004-80390	03/11/04	JP				NO
	AT	2003-219062	07/31/03	JP (equivalent of US2003/137422)				NO
	AU	2002-51135	02/15/02	JP		<u> </u>		NO
	AV	2001-136247	05/18/01	JP .		<u> </u>		NO
		OTHER R	EFERENCES (Including Author, Title, Date, Pertinen	it Pages, e	tc.)		
	AW							
	AX							
	AY							
	AZ				Additional References sheet(s) attached			
Examiner		/Christopher Lei		Date Considered 08/22/2008				
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